

GaAs Semiconductor Laser Diode Single Emitter Structure



PRELIMINARY SPECIFICATION

General Product Information

BA Laser

EYP-BAL-0808-08000-4020-CMT04-0000

308 nm Broad Area Laser Material Proces
nounted on C-Mount Medical
mounted on C-Mount Medical



Absolute Maximum Ratings

	Symbol	Unit	min	typ	max
Storage Temperature	T _s	°C	-40		85
Operational Temperature at Case	T_C	°C	5		40
Forward Current	I _F	А			13
Reverse Voltage	V_R	V			0
Output Power	P_{opt}	W			9

Measurement Conditions / Comments

non	condensing
non	condensing

Stress in excess of the Absolute Maximum Ratings can cause permanent damage to the device. Operation at the Absolute Maximum Rating for extended periods of time can adversely affect the device realibility and may lead to reduced operational life.

Recommended Operational Conditions

	Symbol	Unit	min	typ	max
Operational Temperature at Case	T _C	°C	15		30
Forward Current	I _F	А			12
Output Power	P_{opt}	W			8

	Measurement Cond	itions / Comments
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measured at position A (see drawing on p. 3)

Characteristics at T_{amb} 25 °C at Begin Of Life

Symbol	Unit	min	typ	max
λ_{C}	nm	793	808	823
Δλ	nm			6
dλ / dT	nm / K		0.4	
P _{opt}	W	8		
η_{d}	W/A	0.7	0.9	
I_{th}	А			2.5
	λ_{C} $\Delta\lambda$ $d\lambda$ / dT P_{opt} η_{d}	λ_{C} nm $\Delta\lambda$ nm $d\lambda$ / dT nm / K P_{opt} W η_{d} W / A	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$

Measurement	Conditions I	Comments

see images on page 4

total output measured with integrating sphere



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Characteristics at T_{amb} 25 °C at Begin Of Life

Parameter	Symbol	Unit	min	typ	max
Operational Current @ P _{opt} = 8 W	I _{op}	А			12
Stripe Width	W_s	μm		200	
Cavity Length	L	μm		4000	
Divergence parallel (FWHM)	$\Theta_{ }$	0		10	
Divergence perpendicular (FWHM)	Θ_{\perp}	0		30	
Spectral Mode (longitudinal)				Multi Mode	
Polarization				TM	

Measurement Conditions / Comments
Measurement Conditions / Comments
Polarization in perpendicular plane



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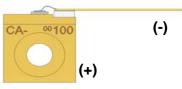
EYP-BAL-0808-08000-4020-CMT04-0000

Symbol	Unit	min	typ	max
I	mm	7.05	7.20	7.35
d	mm		4	
	Symbol I d	l mm	I mm 7.05	l mm 7.05 7.20

Package Pinout

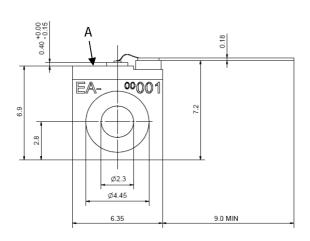
Cathode (-)	Mounting Wire
Anode (+)	Housing

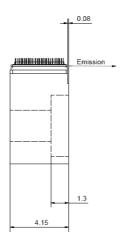
mounting wire



heat spreader

Package Drawings







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RWE/RWL BAL DFB/DBR TPL/TPA

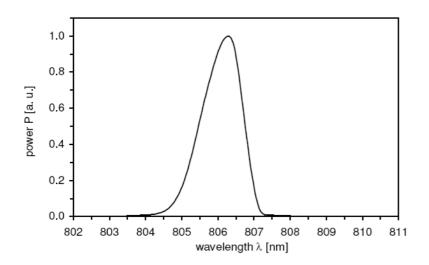
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Typical Measurement Results

Spectrum at Specified Optical Output Power



Performance figures, data and any illustrative material provided in this specification are typical and must be specifically confirmed in writing by eagleyard Photonics before they become applicable to any particular order or contract. In accordance with the eagleyard Photonics policy of continuous improvement specifications may change without notice.

Unpacking, Installation and Laser Safety

Unpacking the laser diodes should only be done at electrostatic safe workstations (EPA). Though protection against electro static discharge (ESD) is implemented in the laser package, charges may occur at surfaces. Please store this product in its original package at a dry, clean place until final use. During device installation, ESD protection has to be maintained.

The BAL diode type is known to be sensitive against thermal stress. Operating at moderate temperatures on propper heat sinks will contribute to a long lifetime of the diode.

The laser emission from this diode is close to the invisible infrared region of the electromagnetic spectrum. Avoid direct and/or indirect exposure to the free running beam. Collimating the free running beam with optics as common in optical instruments will increase thread to the human eye.

Each laser diode will come with an individual test protocol verifying the parameters given in this document.

